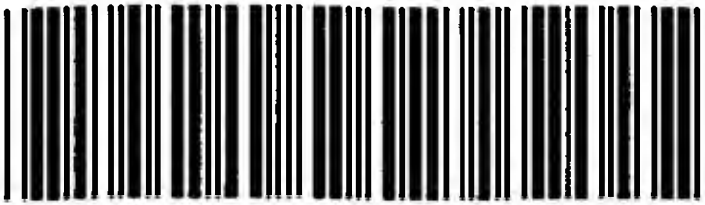


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/604,172	HSU ET AL.	
	Examiner	Art Unit	
	Cheukfan Lee	2625	

SEARCHED			
Class	Subclass	Date	Examiner
358	497	1/31/2008	C.L.
	494		
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382	312		
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399	211		
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250	234-236		
	239		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search: see result, mainly image search	1/31/2008	C.L.
Inventor search		
References only: Han (5,907,413), 66 < 64, Takahashi et al. (5,689,348), front, Yoshida et al. (5,113,268), front		